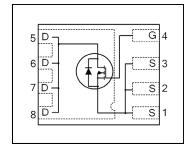


IRFHM8337TRPbF

HEXFET® Power MOSFET

V _{DSS}	30	V
$R_{DS(on)}$ max $(@V_{GS} = 10V)$	12.4	mΩ
(@ V _{GS} = 4.5V)	17.9	
Qg (typical)	5.4	nC
I _D (@T _C = 25°C)	18⑦	Α





Applications

- · System/load switch,
- Charge or discharge switch for battery protection

Features

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Benefits

	Enable better Thermal Dissipation	
results in	Increased Power Density	
\Rightarrow	Multi-Vendor Compatibility	
	Easier Manufacturing	
	Environmentally Friendlier	
	Increased Reliability	

Daga mant number	Standard Pack			Oudenable Deut Neumber
Base part number	Package Type	Form	Quantity	Orderable Part Number
IRFHM8337PbF	PQFN 3.3mm x 3.3mm	Tape and Reel	4000	IRFHM8337TRPbF

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{GS}	Gate-to-Source Voltage	± 20	V
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	12	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	9.4	
I _{DM}	Pulsed Drain Current ①	94®]
I _D @ T _{C(Bottom)} = 25°C	Continuous Drain Current, V _{GS} @ 10V	35⊚⑦	Α
I _D @ T _{C(Bottom)} = 100°C	© T _{C(Bottom)} = 100°C Continuous Drain Current, V _{GS} @ 10V		
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Source Bonding Technology Limited)	18⑦	
P _D @T _A = 25°C	Power Dissipation ©	2.8	10/
P _D @T _{C(Bottom)} = 25°C Power Dissipation ©		25	W
	Linear Derating Factor ©	0.02	W/°C
T_{J}	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		

Notes ① through ® are on page 8

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Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.02		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		9.4	12.4	0	V _{GS} = 10V, I _D = 12A3
, ,			14.5	17.9	mΩ	V _{GS} = 4.5V, I _D =9.4A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.35	1.8	2.35	V	\\ -\\ -25\
$\Delta V_{GS(th)}$	Gate Threshold Voltage Coefficient		-6.2		mV/°C	$V_{DS} = V_{GS}, I_D = 25\mu A$
	Dunin to Course Leakage Current			1.0		$V_{DS} = 24V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			150	μA	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	μΑ	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100		V _{GS} =-20 V
gfs	Forward Transconductance	17			S	$V_{DS} = 15V, I_{D} = 9.4A$
Q_g	Total Gate Charge		5.4	8.1		
Q _{gs1}	Pre-Vth Gate-to-Source Charge		1.1			V _{DS} = 15V
Q_{gs2}	Post-Vth Gate-to-Source Charge		0.7		nC	V _{GS} = 4.5V
Q_{gd}	Gate-to-Drain Charge		2.2			I _D = 9.4A
Q_{godr}	Gate Charge Overdrive		1.5			
Q_{sw}	Switch Charge (Q _{gs2} + Q _{gd})		2.9			
Q_{oss}	Output Charge		3.8		nC	$V_{DS} = 16V, V_{GS} = 0V$
R_G	Gate Resistance		2.0		Ω	
$t_{d(on)}$	Turn-On Delay Time		9.0			$V_{DD} = 15V, V_{GS} = 4.5V$
t _r	Rise Time		11		ns	I _D = 9.4A
$t_{d(off)}$	Turn-Off Delay Time		9.9			R_G = 1.3 Ω
t _f	Fall Time		5.6			
C _{iss}	Input Capacitance		755			V _{GS} = 0V
C _{oss}	Output Capacitance		171		pF	V _{DS} = 15V
C_{rss}	Reverse Transfer Capacitance		83			f = 1.0MHz

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy ②		13	mJ

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current			18⑦		MOSFET symbol
	(Body Diode)					showing the
I _{SM}	Pulsed Source Current			94®	A	integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.0	V	$T_J = 25^{\circ}C$, $I_S = 9.4A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		20	30	ns	$T_J = 25^{\circ}C$, $I_F = 9.4A$, $V_{DD} = 15V$
Q _{rr}	Reverse Recovery Charge		27	41	nC	di/dt = 200A/µs ②

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$ (Bottom)	Junction-to-Case @		5.0	
R _{θJC} (Top)	Junction-to-Case @		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient ®		45	
R _{θJA} (<10s)	Junction-to-Ambient ⑤		31	



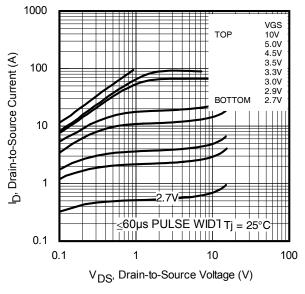


Fig 1. Typical Output Characteristics

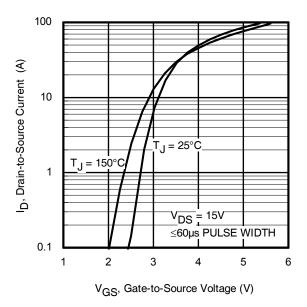


Fig 3. Typical Transfer Characteristics

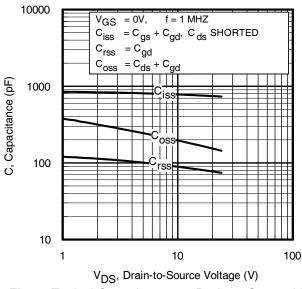


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

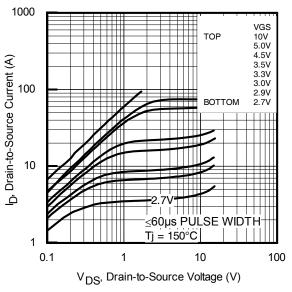


Fig 2. Typical Output Characteristics

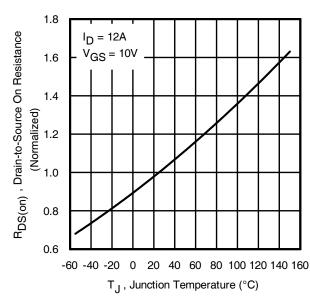


Fig 4. Normalized On-Resistance vs. Temperature

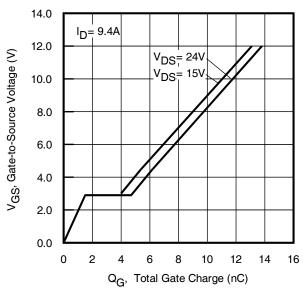


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

2016-2-23



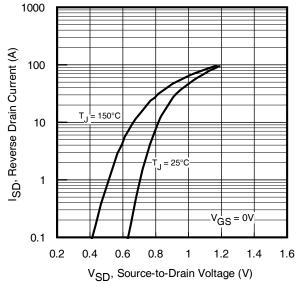


Fig 7. Typical Source-Drain Diode Forward Voltage

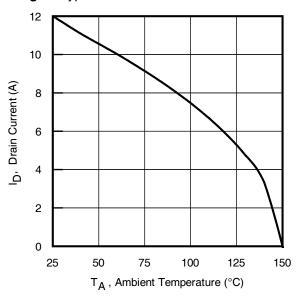


Fig 9. Maximum Drain Current vs. Ambient Temperature

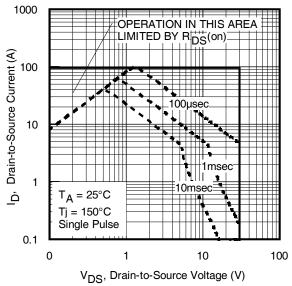


Fig 8. Maximum Safe Operating Area

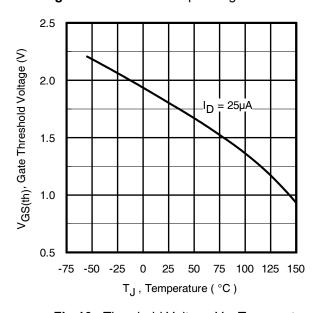


Fig 10. Threshold Voltage Vs. Temperature

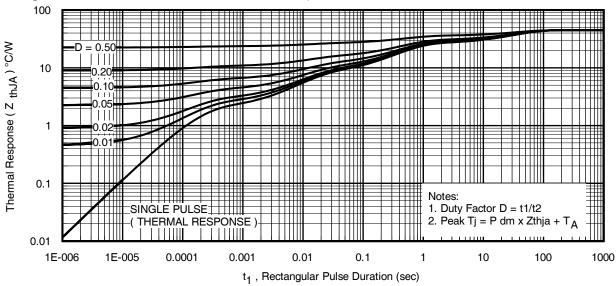
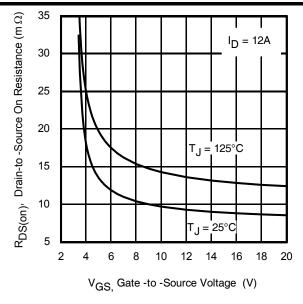


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case





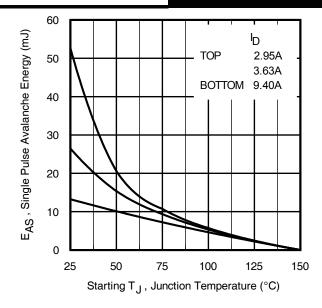


Fig 12. On-Resistance vs. Gate Voltage

Fig 13. Maximum Avalanche Energy vs. Drain Current

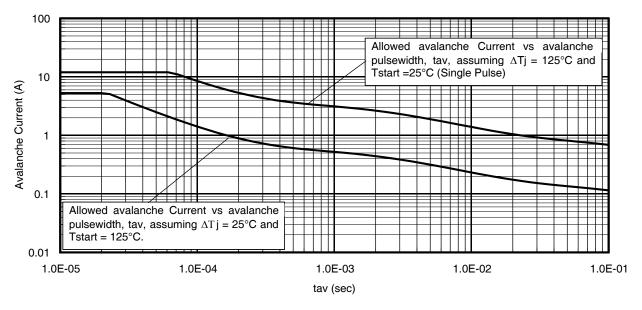


Fig 14. Single avalanche event: pulse current vs. pulse width



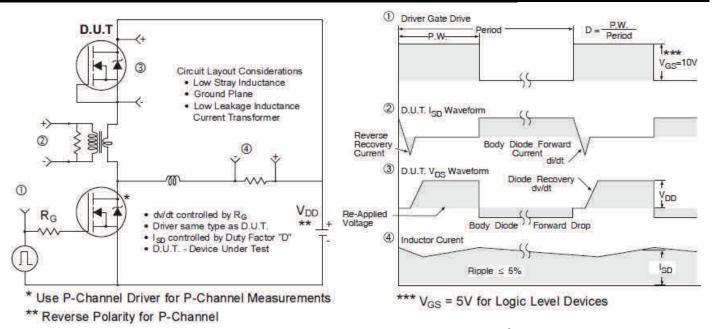


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

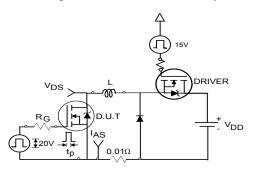


Fig 16a. Unclamped Inductive Test Circuit

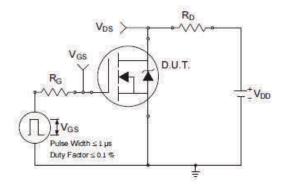


Fig 17a. Switching Time Test Circuit

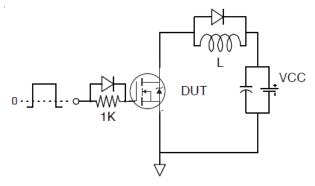


Fig 18. Gate Charge Test Circuit

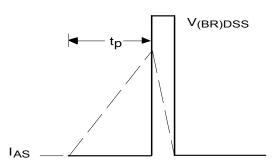


Fig 16b. Unclamped Inductive Waveforms

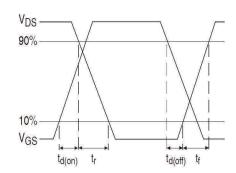


Fig 17b. Switching Time Waveforms

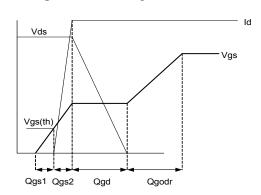


Fig 19. Gate Charge Waveform



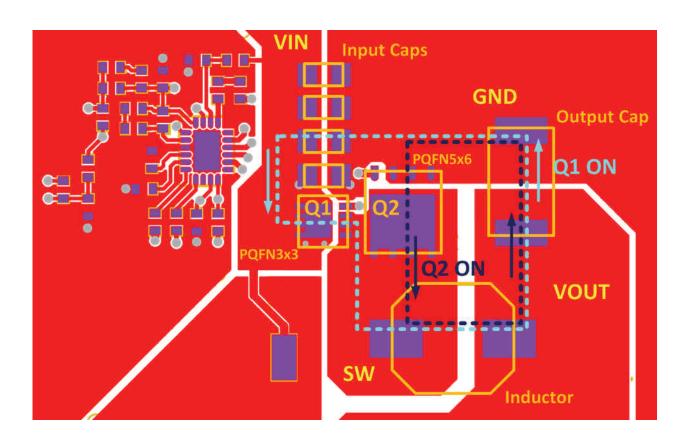
Placement and Layout Guidelines

The typical application topology for this product is the synchronous buck converter. These converters operate at high frequencies (typically around 400 kHz). During turn-on and turn-off switching cycles, the high di/dt currents circulating in the parasitic elements of the circuit induce high voltage ringing which may exceed the device rating and lead to undesirable effects. One of the major contributors to the increase in parasitics is the PCB power circuit inductance.

This section introduces a simple guideline that mitigates the effect of these parasitics on the performance of the circuit and provides reliable operation of the devices.

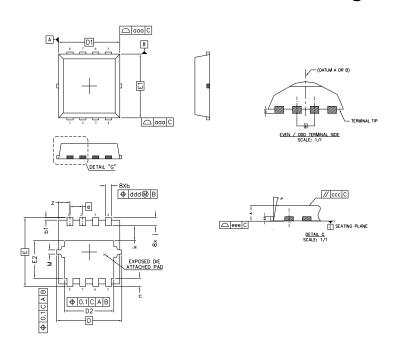
To reduce high frequency switching noise and the effects of Electromagnetic Interference (EMI) when the control MOSFET (Q1) is turned on, the layout shown in Figure 19 is recommended. The input bypass capacitors, control MOSFET and output capacitors are placed in a tight loop to minimize parasitic inductance which in turn lowers the amplitude of the switch node ringing, and minimizes exposure of the MOSFETs to repetitive avalanche conditions.

When the synchronous MOSFET (Q2) is turned on, high average DC current flows through the path indicated in Figure 19. Therefore, the Q2 turn-on path should be laid out with a tight loop and wide traces at both ends of the inductor to minimize loop resistance.



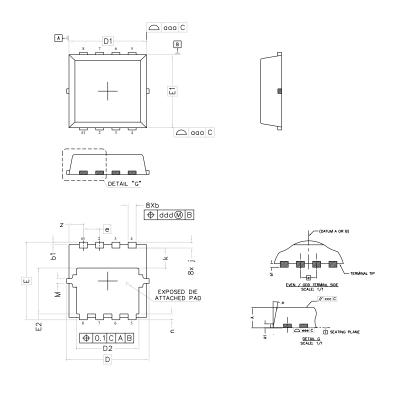


PQFN 3.3 x 3.3 Outline "C" Package Details



5114	MILLIN	METERS	INCH	IES
DIM	MIN	MAX	MIN	MAX
А	0.70	0.80	.0276	.0315
A1	0.10	0.25	.0039	.0098
ь	0.25	0.35	.0098	.0138
b1	0.05	0.15	.0020	.0059
D	3.20	3.40	.1260	.1339
D1	3.00	3.20	.1181	.1260
D2	2.39	2.59	.0941	.1020
E	3.25	3.45	.1280	.1358
E1	3.00	3.20	.1181	.1260
E2	1.78	1.98	.0701	.0780
е	0.65	BSC	.0255 BSC	
j	0.30	0.50	.0118	.0197
k	0.59	0.79	.0232	.0311
n	0.30	0.50	.0118	.0197
М	0.03	0.23	.0012	.0091
Р	10°	12°	10°	12°
z	0.50	0.70	.0197	.0276

PQFN 3.3 x 3.3 Outline "G" Package Details



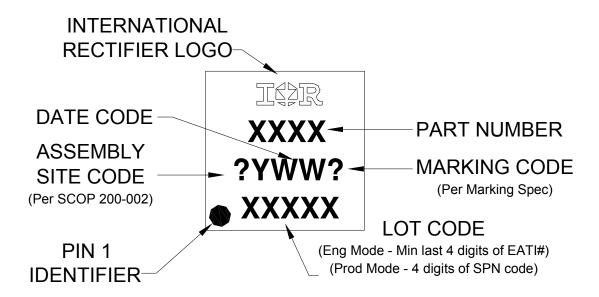
	MILLIN	METERS	INCH	IES	
DIM	MIN MAX		MIN	MAX	
А	0.80	0.90	.0315	.0354	
A1	0.12	0.22	.0047	.0086	
ь	0.22	0.42	.0087	.0165	
b1	0.05	0.15	.0020	.0059	
D	3.30	BSC	.1299	BSC	
D1	3.10	BSC	.1220) BSC	
D2	2.29	2.69	.0902	.1059	
E	3.30 BSC		.1299 BSC		
E1	3.10	BSC	.1220 BSC		
E2	1.85	2.05	.0728	.0807	
е	0.65	BSC	.0255	BSC	
ј	0.15	0.35	.0059	.0137	
k	0.75	0.95	.0295	.0374	
n	0.15	0.35	.0059	.0137	
М	NOM.	0.20	NOM.	.0078	
Р	9°	11°	9°	11°	

For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: http://www.irf.com/technical-info/appnotes/an-1136.pdf

For more information on package inspection techniques, please refer to application note AN-1154: http://www.irf.com/technical-info/appnotes/an-1154.pdf

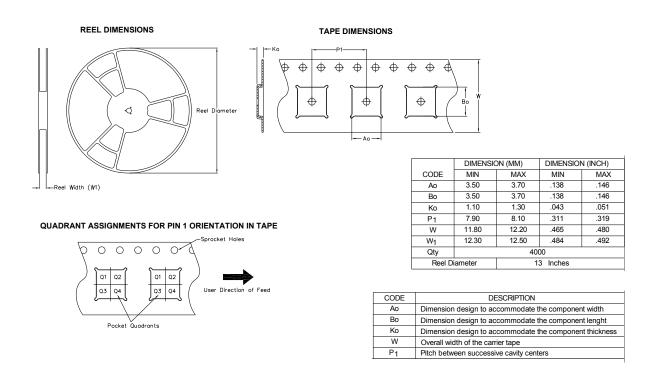


PQFN 3.3 x 3.3 Part Marking



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

PQFN 3.3 x 3.3 Tape and Reel



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information[†]

Qualification Level	Consumer ^{††} (per JEDEC JESD47F guidelines)				
Moisture Sensitivity Level	PQFN 3.3mm x 3.3mm (per JEDEC J-STD-020D ^{†††})				
RoHS Compliant	Yes				

- † Qualification standards can be found at International Rectifier's web site: http://www.irf.com/product-info/reliability/
- †† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: http://www.irf.com/whoto-call/salesrep/
- ††† Applicable version of JEDEC standard at the time of product release.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25$ °C, L = 0.297mH, $R_G = 50\Omega$, $I_{AS} = 9.4$ A.
- 3 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- \P R₀ is measured at TJ of approximately 90°C.
- When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details: http://www.irf.com/technical-info/appnotes/an-994.pdf
- © Calculated continuous current based on maximum allowable junction temperature.
- ② Current limited to 18A by source bonding technology.
- Pulse drain current is limited to 72A by source bonding technology.



Revision History

Date	Comments
6/5/2014	Updated schematic on page 1
	Updated part marking on page 8
	Updated tape and reel on page 9
7/1/2014	Remove "SAWN" package outline on page 8.
02/23/2016	 Updated datasheet with corporate template Updated package outline to reflect the PCN # (241-PCN30-Public) for "Option C" and "Option G" on page 8.

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